MRD 01-02-02

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APPLICANT	"S(S") II		Atty. Docket No.: D/A1090 XER 2 0430			Serial No.: Unknown		
APPLICANT'S(S') INFORMATION DISCLOSURE STATEMENT			Applicant(s): Schweid					
			Filing Date: Herewith		G	Group: Waknewa		
U.S. PATENT DOCUMENTS								
Initial*		Document No.	Date	Name	Class	s Subcl.	Filing Date	
V	AA	4,723,297	02/02/88	Postl				
*	AB	5,001,766	03/19/91	Baird				
4	AC	5,187,753	02/16/93	Bloomberg et al.				
4	AD	5,355,420	10/11/94	Bloomberg et al.				
	AE_				<u> </u>			
	AF							
	AG							
	AH							
	AI							
	AJ							
	AK							
FOREIGN PATENT DOCUMENTS								
		Document No.	Date	Country	Class	s Subcl	Translation?	
	AL							
	AM							
	AN	:						
	AO							
	AP							
OTHER ART								
V	AR	"Accurate Skew Estimation and the Top-Down Analysis of Document Images." Baird, Henry S. December 12, 1986.						
4	AS	"Measuring Document Image Skew and Orientation." Bloomberg et al. SPIE Symposium in Document Recognition II, 1995.						
	ΑT							
Examiner: Date Considered: 7						/19/05		
* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if in conformance and not considered. Include copy of this form with next communication to applicant.								